Search Notes

Application/Control No.	Applicant(s)/Patent und r Reexamination
10/807,541	SHIOZAWA ET AL.
Examiner	Art Unit
Chris C. Chu	2815

SEARCHED					
Class	Subclass	Date	Examiner		
257	685, 686 and 777	1/19/2005	c.c.		
438	108 & 109	1/19/2005	C.C.		
361	760	1/19/2005	C.C.		
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INT	INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner		

SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
Searched in USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB; and USOCR;	1/19/2005	C.C.		
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